





Welcome to **E-XFL.COM**

What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "<u>Embedded - Microcontrollers</u>"

Details	
Product Status	Active
Core Processor	ARM® Cortex®-M0
Core Size	32-Bit Single-Core
Speed	48MHz
Connectivity	HDMI-CEC, I ² C, IrDA, LINbus, SPI, UART/USART
Peripherals	DMA, I ² S, POR, PWM, WDT
Number of I/O	87
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	16K x 8
Voltage - Supply (Vcc/Vdd)	1.65V ~ 3.6V
Data Converters	A/D 19x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	100-LQFP
Supplier Device Package	100-LQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f071v8t7

		3.14.6	SysTick timer	. 23
	3.15	Real-tin	ne clock (RTC) and backup registers	. 23
	3.16	Inter-int	egrated circuit interface (I ² C)	. 24
	3.17	Univers	al synchronous/asynchronous receiver/transmitter (USART)	. 25
	3.18	Serial p	eripheral interface (SPI) / Inter-integrated sound interface (I ² S)	. 26
	3.19	•	efinition multimedia interface (HDMI) - consumer	. 26
	3.20	Clock re	ecovery system (CRS)	. 27
	3.21	Serial w	vire debug port (SW-DP)	. 27
4	Pinou	uts and	pin descriptions	. 28
5	Memo	ory map	pping	. 43
6	Elect	rical ch	aracteristics	. 46
	6.1	Parame	eter conditions	. 46
		6.1.1	Minimum and maximum values	. 46
		6.1.2	Typical values	. 46
		6.1.3	Typical curves	. 46
		6.1.4	Loading capacitor	. 46
		6.1.5	Pin input voltage	. 46
		6.1.6	Power supply scheme	. 47
		6.1.7	Current consumption measurement	. 48
	6.2	Absolut	e maximum ratings	. 49
	6.3	Operati	ng conditions	. 51
		6.3.1	General operating conditions	. 51
		6.3.2	Operating conditions at power-up / power-down	. 51
		6.3.3	Embedded reset and power control block characteristics	. 52
		6.3.4	Embedded reference voltage	. 53
		6.3.5	Supply current characteristics	. 53
		6.3.6	Wakeup time from low-power mode	. 64
		6.3.7	External clock source characteristics	. 64
		6.3.8	Internal clock source characteristics	. 68
		6.3.9	PLL characteristics	. 72
		6.3.10	Memory characteristics	. 72
		6.3.11	EMC characteristics	. 73



Flash memory endurance and data retention	73
EMS characteristics	73
EMI characteristics	74
ESD absolute maximum ratings	75
Electrical sensitivities	
I/O current injection susceptibility	76
I/O static characteristics	76
Output voltage characteristics	79
I/O AC characteristics	80
NRST pin characteristics	81
ADC characteristics	82
R_{AIN} max for f_{ADC} = 14 MHz	84
ADC accuracy	84
DAC characteristics	86
Comparator characteristics	88
TS characteristics	90
V _{BAT} monitoring characteristics	90
TIMx characteristics	90
IWDG min/max timeout period at 40 kHz (LSI)	91
WWDG min/max timeout value at 48 MHz (PCLK)	91
I ² C analog filter characteristics	92
SPI characteristics	
I ² S characteristics	94
UFBGA100 package mechanical data	97
UFBGA100 recommended PCB design rules	98
LQPF100 package mechanical data	100
LQFP64 package mechanical data	103
WLCSP49 package mechanical data	107
LQFP48 package mechanical data	110
UFQFPN48 package mechanical data	113
Package thermal characteristics	115
Ordering information scheme	118
Document revision history	119
	EMS characteristics EMI characteristics ESD absolute maximum ratings Electrical sensitivities I/O current injection susceptibility I/O static characteristics Output voltage characteristics I/O AC characteristics NRST pin characteristics ADC characteristics ADC characteristics ADC characteristics Comparator characteristics Comparator characteristics Ts characteristics Ts characteristics V _{BAT} monitoring characteristics TIMx characteristics IWDG min/max timeout period at 40 kHz (LSI). WWDG min/max timeout value at 48 MHz (PCLK) I ² C analog filter characteristics SPI characteristics UFBGA100 package mechanical data UFBGA100 recommended PCB design rules LQPF100 package mechanical data UFBGA100 recommended PCB design rules LQFP64 package mechanical data UCFP64 package mechanical data UCFP64 package mechanical data UCFP64 package mechanical data UFQFPN48 package mechanical data UFQFPN48 package mechanical data UFQFPN48 package mechanical data Package thermal characteristics Ordering information scheme



3 Functional overview

Figure 1 shows the general block diagram of the STM32F071x8/xB devices.

3.1 ARM®-Cortex®-M0 core

The ARM® Cortex®-M0 is a generation of ARM 32-bit RISC processors for embedded systems. It has been developed to provide a low-cost platform that meets the needs of MCU implementation, with a reduced pin count and low-power consumption, while delivering outstanding computational performance and an advanced system response to interrupts.

The ARM[®] Cortex[®]-M0 processors feature exceptional code-efficiency, delivering the high performance expected from an ARM core, with memory sizes usually associated with 8- and 16-bit devices.

The STM32F071x8/xB devices embed ARM core and are compatible with all ARM tools and software.

3.2 Memories

The device has the following features:

- 16 Kbytes of embedded SRAM accessed (read/write) at CPU clock speed with 0 wait states and featuring embedded parity checking with exception generation for fail-critical applications.
- The non-volatile memory is divided into two arrays:
 - 64 to 128 Kbytes of embedded Flash memory for programs and data
 - Option bytes

The option bytes are used to write-protect the memory (with 4 KB granularity) and/or readout-protect the whole memory with the following options:

- Level 0: no readout protection
- Level 1: memory readout protection, the Flash memory cannot be read from or written to if either debug features are connected or boot in RAM is selected
- Level 2: chip readout protection, debug features (Cortex[®]-M0 serial wire) and boot in RAM selection disabled

3.3 Boot modes

At startup, the boot pin and boot selector option bit are used to select one of the three boot options:

- boot from User Flash memory
- boot from System Memory
- boot from embedded SRAM

The boot loader is located in System Memory. It is used to reprogram the Flash memory by using USART on pins PA14/PA15, or PA9/PA10 or I²C on pins PB6/PB7.

3.9.2 Extended interrupt/event controller (EXTI)

The extended interrupt/event controller consists of 32 edge detector lines used to generate interrupt/event requests and wake-up the system. Each line can be independently configured to select the trigger event (rising edge, falling edge, both) and can be masked independently. A pending register maintains the status of the interrupt requests. The EXTI can detect an external line with a pulse width shorter than the internal clock period. Up to 87 GPIOs can be connected to the 16 external interrupt lines.

3.10 Analog-to-digital converter (ADC)

The 12-bit analog-to-digital converter has up to 16 external and 3 internal (temperature sensor, voltage reference, VBAT voltage measurement) channels and performs conversions in single-shot or scan modes. In scan mode, automatic conversion is performed on a selected group of analog inputs.

The ADC can be served by the DMA controller.

An analog watchdog feature allows very precise monitoring of the converted voltage of one, some or all selected channels. An interrupt is generated when the converted voltage is outside the programmed thresholds.

3.10.1 Temperature sensor

The temperature sensor (TS) generates a voltage V_{SENSE} that varies linearly with temperature.

The temperature sensor is internally connected to the ADC_IN16 input channel which is used to convert the sensor output voltage into a digital value.

The sensor provides good linearity but it has to be calibrated to obtain good overall accuracy of the temperature measurement. As the offset of the temperature sensor varies from chip to chip due to process variation, the uncalibrated internal temperature sensor is suitable for applications that detect temperature changes only.

To improve the accuracy of the temperature sensor measurement, each device is individually factory-calibrated by ST. The temperature sensor factory calibration data are stored by ST in the system memory area, accessible in read-only mode.

Calibration value name	Description	Memory address
TS_CAL1	TS ADC raw data acquired at a temperature of 30 °C (± 5 °C), V _{DDA} = 3.3 V (± 10 mV)	0x1FFF F7B8 - 0x1FFF F7B9
TS_CAL2	TS ADC raw data acquired at a temperature of 110 °C (± 5 °C), V _{DDA} = 3.3 V (± 10 mV)	0x1FFF F7C2 - 0x1FFF F7C3

Table 3. Temperature sensor calibration values

3.10.2 Internal voltage reference (V_{REFINT})

The internal voltage reference (V_{REFINT}) provides a stable (bandgap) voltage output for the ADC and comparators. V_{REFINT} is internally connected to the ADC_IN17 input channel. The

18/122 DocID025451 Rev 6



Table 6. Number of capacitive sensing channels available on STM32F071x8/xB devices

Analog I/O group	Number of capacitive sensing channels						
Analog I/O group	STM32F071Vx	STM32F071Rx	STM32F071Cx				
G1	3	3	3				
G2	3	3	3				
G3	3	3	2				
G4	3	3	3				
G5	3	3	3				
G6	3	3	3				
G7	3	0	0				
G8	3	0	0				
Number of capacitive sensing channels	24	18	17				

3.14 Timers and watchdogs

The STM32F071x8/xB devices include up to six general-purpose timers, two basic timers and an advanced control timer.

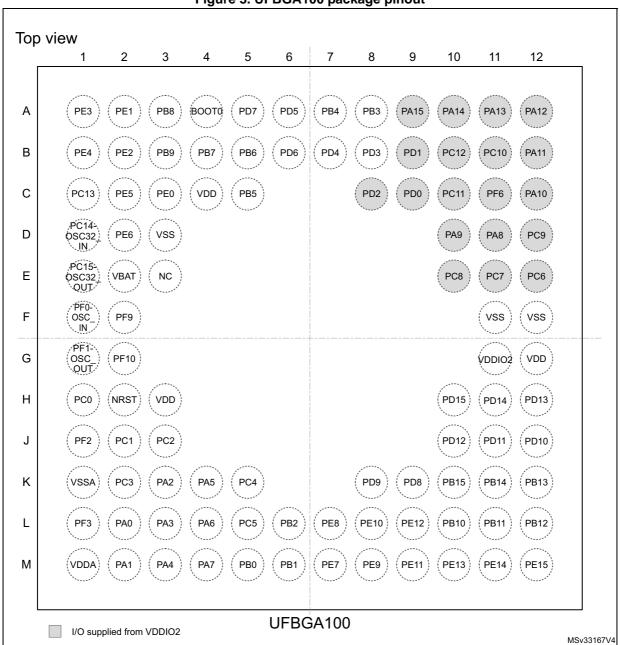
Table 7 compares the features of the different timers.

Table 7. Timer feature comparison

Timer type	Timer	Counter resolution	Counter type	Prescaler factor	DMA request generation	Capture/compare channels	Complementary outputs
Advanced control	TIM1	16-bit	Up, down, up/down	integer from 1 to 65536	Yes	4	3
	TIM2	32-bit	Up, down, up/down	integer from 1 to 65536	Yes	4	-
	TIM3	16-bit	Up, down, up/down	integer from 1 to 65536	Yes	4	-
General purpose	TIM14	16-bit	Up	integer from 1 to 65536	No	1	-
	TIM15	16-bit	Up	integer from 1 to 65536	Yes	2	1
	TIM16 TIM17	16-bit	Up	integer from 1 to 65536	Yes	1	1
Basic	TIM6 TIM7	16-bit	Up	integer from 1 to 65536	Yes	-	-

4 Pinouts and pin descriptions

Figure 3. UFBGA100 package pinout



28/122 DocID025451 Rev 6

Table 18. Alternate functions selected through GPIOE_AFR registers for port E

Pin name	AF0	AF1
PE0	TIM16_CH1	EVENTOUT
PE1	TIM17_CH1	EVENTOUT
PE2	TIM3_ETR	TSC_G7_IO1
PE3	TIM3_CH1	TSC_G7_IO2
PE4	TIM3_CH2	TSC_G7_IO3
PE5	TIM3_CH3	TSC_G7_IO4
PE6	TIM3_CH4	-
PE7	TIM1_ETR	-
PE8	TIM1_CH1N	-
PE9	TIM1_CH1	-
PE10	TIM1_CH2N	-
PE11	TIM1_CH2	-
PE12	TIM1_CH3N	SPI1_NSS, I2S1_WS
PE13	TIM1_CH3	SPI1_SCK, I2S1_CK
PE14	TIM1_CH4	SPI1_MISO, I2S1_MCK
PE15	TIM1_BKIN	SPI1_MOSI, I2S1_SD

Table 19. Alternate functions available on port F

	The second contract of
Pin name	AF
PF0	CRS_SYNC
PF1	-
PF2	EVENTOUT
PF3	EVENTOUT
PF6	-
PF9	TIM15_CH1
PF10	TIM15_CH2

42/122 DocID025451 Rev 6

5 Memory mapping

To the difference of STM32F071xB memory map in *Figure 9*, the two bottom code memory spaces of STM32F071x8 end at 0x0000 FFFF and 0x0800 FFFF, respectively.

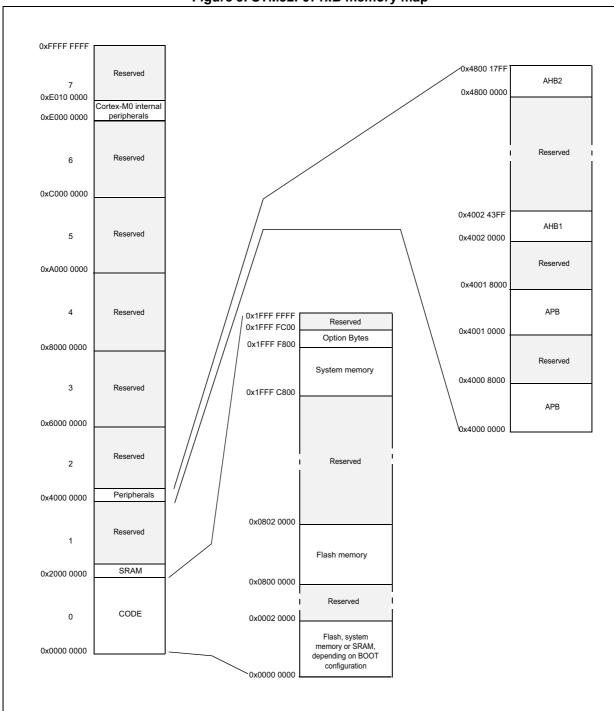


Figure 9. STM32F071xB memory map

MS31409V2

6 Electrical characteristics

6.1 Parameter conditions

Unless otherwise specified, all voltages are referenced to V_{SS}.

6.1.1 Minimum and maximum values

Unless otherwise specified, the minimum and maximum values are guaranteed in the worst conditions of ambient temperature, supply voltage and frequencies by tests in production on 100% of the devices with an ambient temperature at $T_A = 25$ °C and $T_A = T_A$ max (given by the selected temperature range).

Data based on characterization results, design simulation and/or technology characteristics are indicated in the table footnotes and are not tested in production. Based on characterization, the minimum and maximum values refer to sample tests and represent the mean value plus or minus three times the standard deviation (mean $\pm 3\sigma$).

6.1.2 Typical values

Unless otherwise specified, typical data are based on $T_A = 25$ °C, $V_{DD} = V_{DDA} = 3.3$ V. They are given only as design guidelines and are not tested.

Typical ADC accuracy values are determined by characterization of a batch of samples from a standard diffusion lot over the full temperature range, where 95% of the devices have an error less than or equal to the value indicated (mean $\pm 2\sigma$).

6.1.3 Typical curves

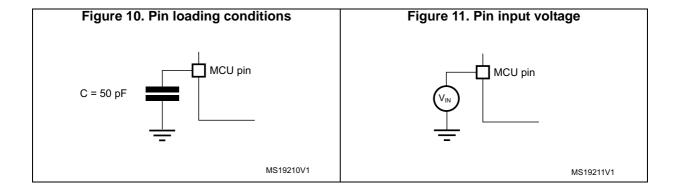
Unless otherwise specified, all typical curves are given only as design guidelines and are not tested.

6.1.4 Loading capacitor

The loading conditions used for pin parameter measurement are shown in *Figure 10*.

6.1.5 Pin input voltage

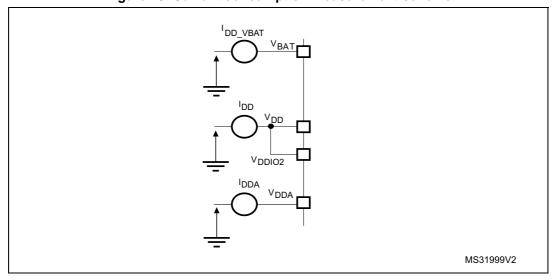
The input voltage measurement on a pin of the device is described in Figure 11.



577

6.1.7 Current consumption measurement

Figure 13. Current consumption measurement scheme



Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V	PVD threshold 6	Rising edge	2.66	2.78	2.9	V
V _{PVD6}	F VD tillesiloid o	Falling edge	2.56	2.68	2.8	V
V	PVD threshold 7	Rising edge	2.76	2.88	3	V
V _{PVD7}	FVD tillesiloid /	Falling edge	2.66	2.78	2.9	V
V _{PVDhyst} ⁽¹⁾	PVD hysteresis	-	-	100	-	mV
I _{DD(PVD)}	PVD current consumption	-	-	0.15	0.26 ⁽¹⁾	μA

Table 27. Programmable voltage detector characteristics (continued)

6.3.4 Embedded reference voltage

The parameters given in *Table 28* are derived from tests performed under the ambient temperature and supply voltage conditions summarized in *Table 24: General operating conditions*.

lable 20. Emboaded internal relevance vellage										
Symbol	Parameter	Min	Тур	Max	Unit					
V_{REFINT}	Internal reference voltage	-40 °C < T _A < +105 °C	1.2	1.23	1.25	V				
t _{START}	ADC_IN17 buffer startup time	-	-	-	10 ⁽¹⁾	μs				
t _{S_vrefint}	ADC sampling time when reading the internal reference voltage	-	4 ⁽¹⁾	-	-	μs				
ΔV_{REFINT}	Internal reference voltage spread over the temperature range	V _{DDA} = 3 V	-	-	10 ⁽¹⁾	mV				
T _{Coeff}	Temperature coefficient	-	- 100 ⁽¹⁾	-	100 ⁽¹⁾	ppm/°C				

Table 28. Embedded internal reference voltage

6.3.5 Supply current characteristics

The current consumption is a function of several parameters and factors such as the operating voltage, ambient temperature, I/O pin loading, device software configuration, operating frequencies, I/O pin switching rate, program location in memory and executed binary code.

The current consumption is measured as described in *Figure 13: Current consumption measurement scheme*.

All Run-mode current consumption measurements given in this section are performed with a reduced code that gives a consumption equivalent to CoreMark code.

^{1.} Guaranteed by design, not tested in production.

^{1.} Guaranteed by design, not tested in production.

Table 31. Typical and maximum consumption in Stop and Standby modes

Sym- Para-				Typ @V _{DD} (V _{DD} = V _{DDA})					Max ⁽¹⁾					
bol			Conditions		2.4 V	2.7 V	3.0 V	3.3 V	3.6 V	T _A = 25 °C	T _A = 85 °C	T _A = 105 °C	Unit	
	Supply current in	mod	julator in run de, all illators OFF	15.4	15.5	15.6	15.7	15.8	15.9	23 ⁽²⁾	49	68 ⁽²⁾		
I _{DD}	Stop mode	pow	julator in low- ver mode, all illators OFF	3.2	3.3	3.4	3.5	3.6	3.7	8 ⁽²⁾	33	51 ⁽²⁾		
	Supply current in	LSI ON	ON and IWDG	0.8	1.0	1.1	1.2	1.3	1.4	-	-	-		
	Standby mode	LSI OFF	OFF and IWDG	0.6	0.7	0.9	0.9	1.0	1.1	2.1 ⁽²⁾	2.6	3.1 ⁽²⁾		
	Supply current in Stop mode	NO	Regulator in run mode, all oscillators OFF	2.1	2.2	2.3	2.5	2.6	2.8	3.5 ⁽²⁾	3.6	4.6 ⁽²⁾		
		V _{DDA} monitoring O	Regulator in low-power mode, all oscillators OFF	2.1	2.2	2.3	2.5	2.6	2.8	3.5 ⁽²⁾	3.6	4.6 ⁽²⁾	μА	
	Supply current in	V _{DI}	LSI ON and IWDG ON	2.5	2.7	2.8	3.0	3.2	3.5	-	-	-		
loo.	Standby mode		LSI OFF and IWDG OFF	1.9	2.1	2.2	2.3	2.5	2.6	3.5 ⁽²⁾	3.6	4.6 ⁽²⁾		
I _{DDA}	Supply current in Stop mode	Supply	-F	Regulator in run mode, all oscillators OFF	1.3	1.3	1.4	1.4	1.5	1.5	-	-	-	
		V _{DDA} monitoring OFF	Regulator in low-power mode, all oscillators OFF	1.3	1.3	1.4	1.4	1.5	1.5	-	-	-		
	Supply current in	V _{DD}	LSI ON and IWDG ON	1.7	1.8	1.9	2.0	2.1	2.2	1	-	1		
	Standby		LSI OFF and IWDG OFF	1.2	1.2	1.2	1.3	1.3	1.4	-	-	-		

^{1.} Data based on characterization results, not tested in production unless otherwise specified.

^{2.} Data based on characterization results and tested in production (using one common test limit for sum of I_{DD} and I_{DDA}).

trigger circuits used to discriminate the input value. Unless this specific configuration is required by the application, this supply current consumption can be avoided by configuring these I/Os in analog mode. This is notably the case of ADC input pins which should be configured as analog inputs.

Caution:

Any floating input pin can also settle to an intermediate voltage level or switch inadvertently, as a result of external electromagnetic noise. To avoid current consumption related to floating pins, they must either be configured in analog mode, or forced internally to a definite digital value. This can be done either by using pull-up/down resistors or by configuring the pins in output mode.

I/O dynamic current consumption

In addition to the internal peripheral current consumption measured previously (see *Table 35: Peripheral current consumption*), the I/Os used by an application also contribute to the current consumption. When an I/O pin switches, it uses the current from the I/O supply voltage to supply the I/O pin circuitry and to charge/discharge the capacitive load (internal or external) connected to the pin:

$$I_{SW} = V_{DDIOx} \times f_{SW} \times C$$

where

 $I_{\mbox{\scriptsize SW}}$ is the current sunk by a switching I/O to charge/discharge the capacitive load

V_{DDIOx} is the I/O supply voltage

f_{SW} is the I/O switching frequency

C is the total capacitance seen by the I/O pin: $C = C_{INT} + C_{EXT} + C_{S}$

C_S is the PCB board capacitance including the pad pin.

The test pin is configured in push-pull output mode and is toggled by software at a fixed frequency.



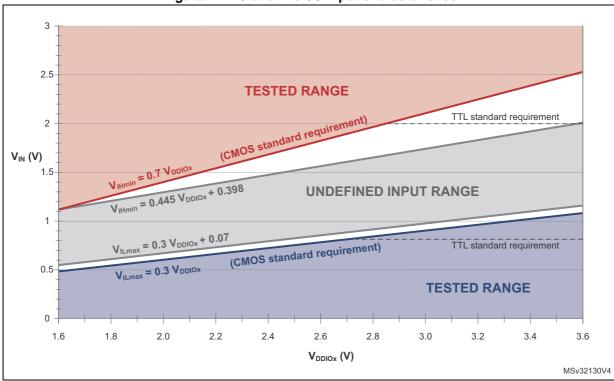
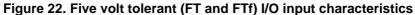
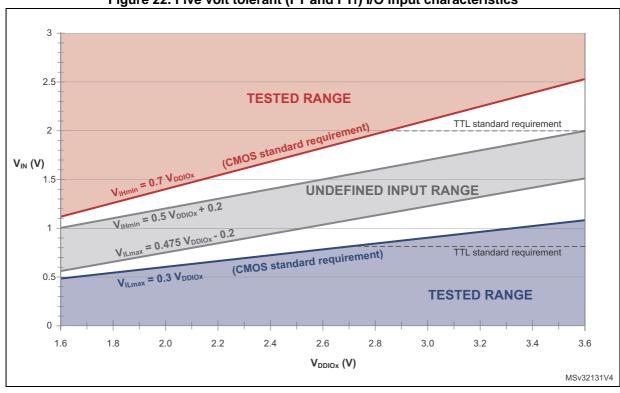


Figure 21. TC and TTa I/O input characteristics





57

OSPEEDRy [1:0] value ⁽¹⁾	Symbol	Parameter	Conditions	Min	Max	Unit
	f _{max(IO)out}	Maximum frequency ⁽³⁾			2	MHz
Fm+ configuration (4)	$t_{f(IO)out}$	Output fall time	$C_L = 50 \text{ pF}, V_{DDIOx} \ge 2 \text{ V}$	-	12	ns
	t _{r(IO)out}	Output rise time		-	34	
	f _{max(IO)out}	Maximum frequency ⁽³⁾		-	0.5	MHz
	t _{f(IO)out}	Output fall time	C _L = 50 pF, V _{DDIOx} < 2 V	-	16	ns
	t _{r(IO)out}	Output rise time			44	115
-	t _{EXTIpw}	Pulse width of external signals detected by the EXTI controller	-	10	1	ns

Table 55. I/O AC characteristics⁽¹⁾⁽²⁾ (continued)

- The I/O speed is configured using the OSPEEDRx[1:0] bits. Refer to the STM32F0xxxx RM0091 reference manual for a description of GPIO Port configuration register.
- 2. Guaranteed by design, not tested in production.
- 3. The maximum frequency is defined in Figure 23.
- When Fm+ configuration is set, the I/O speed control is bypassed. Refer to the STM32F0xxxx reference manual RM0091 for a detailed description of Fm+ I/O configuration.

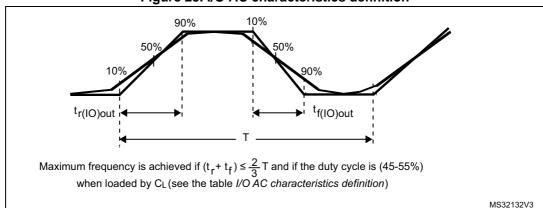


Figure 23. I/O AC characteristics definition

6.3.15 NRST pin characteristics

The NRST pin input driver uses the CMOS technology. It is connected to a permanent pull-up resistor, R_{PU} .

Unless otherwise specified, the parameters given in the table below are derived from tests performed under the ambient temperature and supply voltage conditions summarized in *Table 24: General operating conditions*.

 Symbol
 Parameter
 Conditions
 Min
 Typ
 Max
 Unit

 V_{IL(NRST)}
 NRST input low level voltage
 0.3 V_{DD}+0.07⁽¹⁾
 V

 V_{IH(NRST)}
 NRST input high level voltage
 0.445 V_{DD}+0.398⁽¹⁾

Table 56. NRST pin characteristics

7.2 LQFP100 package information

LQFP100 is a100-pin, 14 x 14 mm low-profile quad flat package.

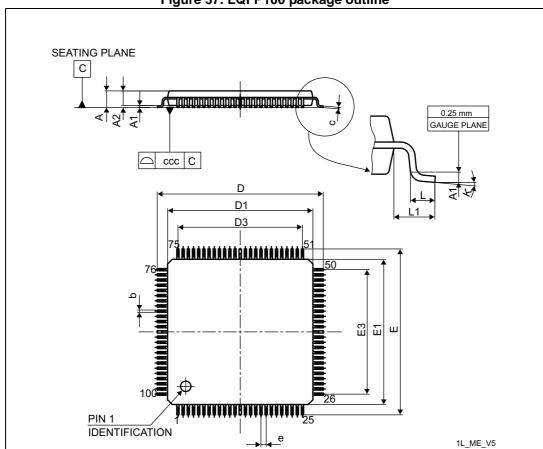


Figure 37. LQFP100 package outline

1. Drawing is not to scale.

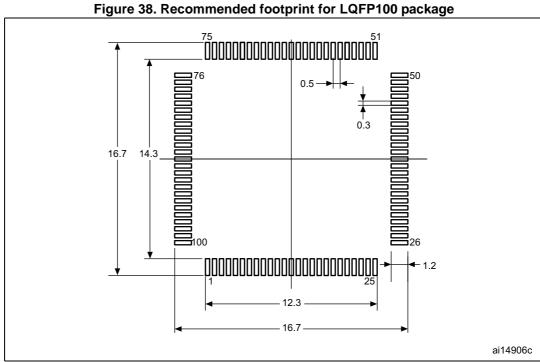
Table 72. LQPF100 package mechanical data

Symbol	millimeters			inches ⁽¹⁾		
	Min	Тур	Max	Min	Тур	Max
А	-	-	1.600	-	-	0.0630
A1	0.050	-	0.150	0.0020	-	0.0059
A2	1.350	1.400	1.450	0.0531	0.0551	0.0571
b	0.170	0.220	0.270	0.0067	0.0087	0.0106
С	0.090	-	0.200	0.0035	-	0.0079
D	15.800	16.000	16.200	0.6220	0.6299	0.6378
D1	13.800	14.000	14.200	0.5433	0.5512	0.5591
D3	-	12.000	-	-	0.4724	-
Е	15.800	16.000	16.200	0.6220	0.6299	0.6378

inches⁽¹⁾ millimeters **Symbol** Min Тур Max Min Тур Max 13.800 14.000 14.200 0.5433 0.5512 0.5591 E1 E3 0.4724 12.000 0.500 0.0197 е L 0.450 0.600 0.750 0.0177 0.0236 0.0295 1.000 0.0394 L1 3.5° 0.0° 7.0° 0.0° 7.0° 3.5° k 0.080 0.0031 CCC

Table 72. LQPF100 package mechanical data (continued)

^{1.} Values in inches are converted from mm and rounded to 4 decimal digits.



1. Dimensions are expressed in millimeters.

Table 76. UFQFPN48 package mechanical data

				:(1)			
Symbol	millimeters			inches ⁽¹⁾			
	Min	Тур	Max	Min	Тур	Max	
Α	0.500	0.550	0.600	0.0197	0.0217	0.0236	
A1	0.000	0.020	0.050	0.0000	0.0008	0.0020	
D	6.900	7.000	7.100	0.2717	0.2756	0.2795	
E	6.900	7.000	7.100	0.2717	0.2756	0.2795	
D2	5.500	5.600	5.700	0.2165	0.2205	0.2244	
E2	5.500	5.600	5.700	0.2165	0.2205	0.2244	
L	0.300	0.400	0.500	0.0118	0.0157	0.0197	
Т	-	0.152	-	-	0.0060	-	
b	0.200	0.250	0.300	0.0079	0.0098	0.0118	
е	-	0.500	-	-	0.0197	-	
ddd	-	-	0.080	-	-	0.0031	

^{1.} Values in inches are converted from mm and rounded to 4 decimal digits.

7.30

0.20

0.30

0.30

0.55

0.560

0.50

0.75

A0B9_FP_V2

1. Dimensions are expressed in millimeters.

As applications do not commonly use the STM32F071x8/xB at maximum dissipation, it is useful to calculate the exact power consumption and junction temperature to determine which temperature range will be best suited to the application.

The following examples show how to calculate the temperature range needed for a given application.

Example 1: High-performance application

Assuming the following application conditions:

Maximum temperature T_{Amax} = 82 °C (measured according to JESD51-2), I_{DDmax} = 50 mA, V_{DD} = 3.5 V, maximum 20 I/Os used at the same time in output at low level with I_{OL} = 8 mA, V_{OL} = 0.4 V and maximum 8 I/Os used at the same time in output at low level with I_{OL} = 20 mA, V_{OL} = 1.3 V

 $P_{INTmax} = 50 \text{ mA} \times 3.5 \text{ V} = 175 \text{ mW}$

 $P_{IOmax} = 20 \times 8 \text{ mA} \times 0.4 \text{ V} + 8 \times 20 \text{ mA} \times 1.3 \text{ V} = 272 \text{ mW}$

This gives: P_{INTmax} = 175 mW and P_{IOmax} = 272 mW:

 P_{Dmax} = 175 + 272 = 447 mW

Using the values obtained in $Table 77 T_{Jmax}$ is calculated as follows:

For LQFP64, 45 °C/W

$$T_{Jmax}$$
 = 82 °C + (45 °C/W × 447 mW) = 82 °C + 20.115 °C = 102.115 °C

This is within the range of the suffix 6 version parts ($-40 < T_{.l} < 105$ °C).

In this case, parts must be ordered at least with the temperature range suffix 6 (see Section 8: Ordering information).

Note:

With this given P_{Dmax} we can find the T_{Amax} allowed for a given device temperature range (order code suffix 6 or 7).

Suffix 6:
$$T_{Amax} = T_{Jmax}$$
 - $(45^{\circ}\text{C/W} \times 447 \text{ mW}) = 105\text{-}20.115 = 84.885 ^{\circ}\text{C}$
Suffix 7: $T_{Amax} = T_{Jmax}$ - $(45^{\circ}\text{C/W} \times 447 \text{ mW}) = 125\text{-}20.115 = 104.885 ^{\circ}\text{C}$

Example 2: High-temperature application

Using the same rules, it is possible to address applications that run at high temperatures with a low dissipation, as long as junction temperature T_J remains within the specified range.

Assuming the following application conditions:

Maximum temperature T_{Amax} = 100 °C (measured according to JESD51-2), I_{DDmax} = 20 mA, V_{DD} = 3.5 V, maximum 20 I/Os used at the same time in output at low level with I_{OL} = 8 mA, V_{OL} = 0.4 V

 P_{INTmax} = 20 mA × 3.5 V= 70 mW

 $P_{IOmax} = 20 \times 8 \text{ mA} \times 0.4 \text{ V} = 64 \text{ mW}$

This gives: P_{INTmax} = 70 mW and P_{IOmax} = 64 mW:

 $P_{Dmax} = 70 + 64 = 134 \text{ mW}$

Thus: P_{Dmax} = 134 mW

Using the values obtained in *Table 77* T_{Jmax} is calculated as follows:

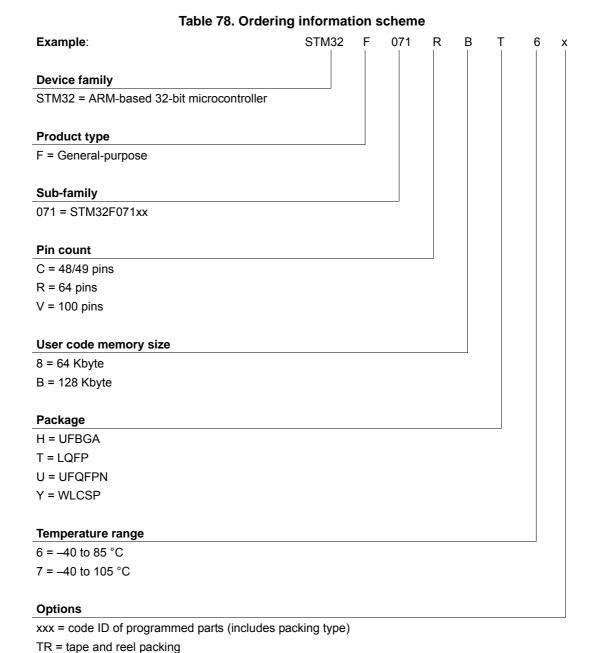
For LQFP64, 45 °C/W

 T_{Jmax} = 100 °C + (45 °C/W × 134 mW) = 100 °C + 6.03 °C = 106.03 °C

5//

8 Ordering information

For a list of available options (memory, package, and so on) or for further information on any aspect of this device, please contact your nearest ST sales office.



47/

blank = tray packing